


<b>Search Notes</b>  	<b>Application/Control No.</b>  10511217	<b>Applicant(s)/Patent Under Reexamination</b>  MONTVAY ET AL.
	<b>Examiner</b>  Kim, Hee Soo	<b>Art Unit</b>  2109

SEARCHED			
Class	Subclass	Date	Examiner
370	60-61, 79	4/27/2007	HSK
709	201-253	4/27/2007	HSK
395	200.11	4/27/2007	HSK
455	550, 560	4/27/2007	

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor Search	4/27/2007	HSK
George Neurauter (PS) at TC2100 search help	4/27/2007	HSK
Mustafa Meky (Primary/Search Mentor) search help	4/27/2007	HSK
William Vaughn (SPE) search help	4/27/2007	HSK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner